

Resource Summary Report

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Horiba: Auto SE Spectroscopic Ellipsometer for Thin Film Measurement

RRID:SCR_020030

Type: Tool

Proper Citation

Horiba: Auto SE Spectroscopic Ellipsometer for Thin Film Measurement
(RRID:SCR_020030)

Resource Information

URL: https://www.horiba.com/en_en/products/detail/action/show/Product/auto-se-1432/

Proper Citation: Horiba: Auto SE Spectroscopic Ellipsometer for Thin Film Measurement
(RRID:SCR_020030)

Description: Thin film measurement tool that allows full automatic analysis of thin film samples with push button operation. It includes automatic XYZ stage, real time imaging of measurement site and automatic selection of spot size.

Resource Type: instrument resource

Keywords: Horiba, Spectroscopic Ellipsometer for Thin Film Measurement, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: Horiba: Auto SE Spectroscopic Ellipsometer for Thin Film Measurement

Resource ID: SCR_020030

Alternate IDs: Model_Number_Auto SE

Record Creation Time: 20220129T080348+0000

Record Last Update: 20260912T195927+0000

Ratings and Alerts

No rating or validation information has been found for Horiba: Auto SE Spectroscopic Ellipsometer for Thin Film Measurement.

No alerts have been found for Horiba: Auto SE Spectroscopic Ellipsometer for Thin Film Measurement.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.